

Search Notes**Application/Control No.**

10/538,668

Examiner

THANH S. PHAN

**Applicant(s)/Patent under
Reexamination**

BOUILLE, ERIC

Art Unit

2833

SEARCHED

Class	Subclass	Date	Examiner
368	281	9/28/2007	TSP
224	164, 167,		
	169		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east search	3/17/2008	TSP